

Search Notes

Application/Control No.

10/724,151

Examiner

Erin M. File

Applicant(s)/Patent under
Reexamination

JEONG ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	371	1/17/2007	EMF
375	373	1/17/2007	EMF
375	376	1/17/2007	EMF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	1/17/2007	EMF
PALM INVENTORSHIP	1/17/2007	EMF
PLUS Search	1/17/2007	EMF